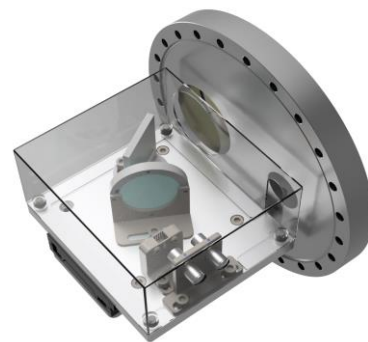
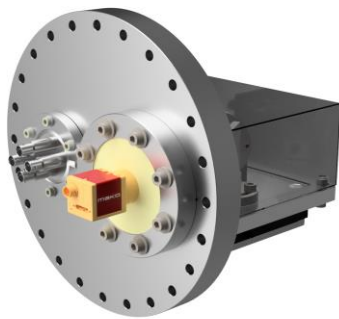


## SCIENTIFIC INSTRUMENTATION

### nanoLIGHT

#### Integrated XUV spectrometer and beam profiler

This compact and versatile device makes XUV beam characterization easy: the nanoLIGHT combines the functionalities of an XUV spectrometer and an XUV beam profiler in one unit. It is quickly integrated into experimental setups: the entire device is mounted on a standard CF200 vacuum flange. Switching between operating modes or removal from the XUV beam path is completed within seconds.



#### Versatility

- two functionalities in one compact device
- fast switching between modes and transmission
- effortless integration
- integrated spectral filter insert
- integrated background light reduction
- compact and cost-effective

#### Efficiency and sensitivity

- wide spectral coverage: 10-80nm recorded simultaneously
- high overall efficiency
- large dynamic range due to MCP detection
- sensitivity adjustable, up to single photon counting regime
- low background noise

## Characteristics

- In-situ XUV spectrometer and beam profiler
- Compact footprint (16x17cm<sup>2</sup>)
- Cost-effective
- Quick mode switching
- Wavelength coverage 10 - 80nm, recorded simultaneously
- Insert for thin metal spectral filters
- Background light reduction jig
- Customizable according to user requirements

	XUV grating	other gratings
<b>Spectrometer mode</b>		
Wavelength [nm]	10 - 80	on request
Resolution [nm]	0.13 - 0.25	
Grating efficiency	~20%	
MCP efficiency	~20%	
<b>Beam profiler mode</b>		
Resolution [um]	100	

\* Other configurations (spectral range, etc) available upon request.

## Grating efficiency

